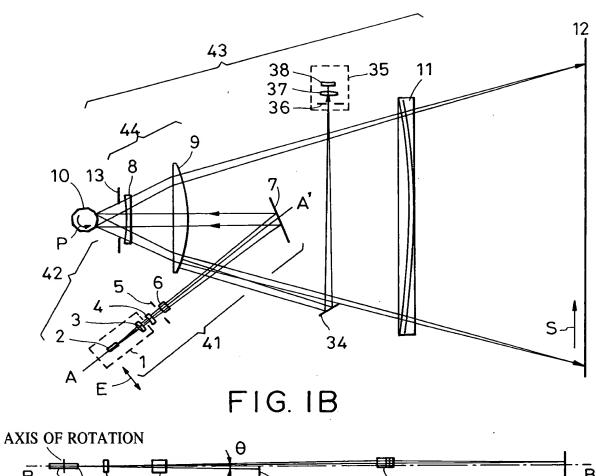
FIG. IA



12

FIG. IC

SECTION TAKEN ALONG LINE AA'

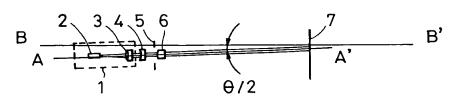
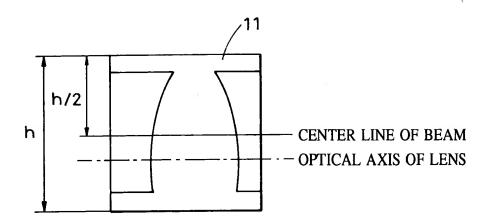


FIG. 2



## FIG. 3A

## WITH SEMICONDUCTOR LASER CHIP NOT TILTED

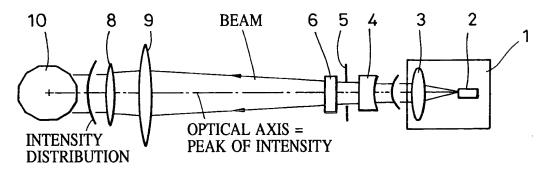


FIG. 3B

WITH SEMICONDUCTOR LASER CHIP TILTED

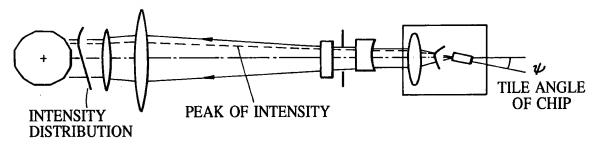


FIG. 3C

WITH SEMICONDUCTOR LASER CHIP SHIFTED

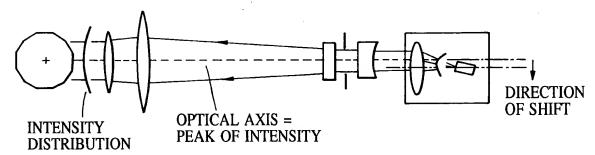


FIG. 4A

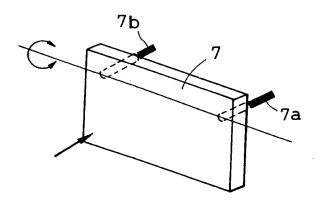


FIG. 4B



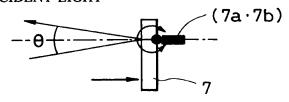


FIG. 5A

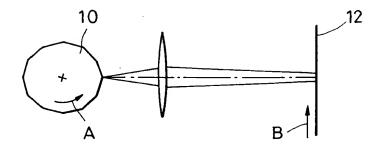


FIG. 5B

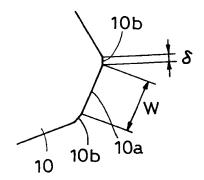
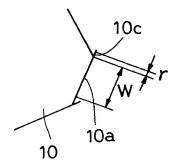


FIG. 6



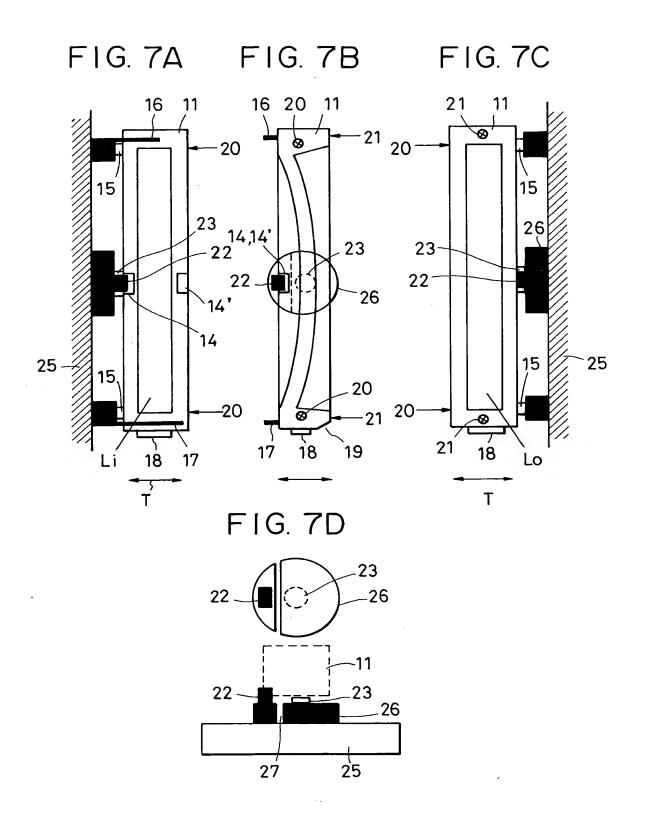


FIG. 8

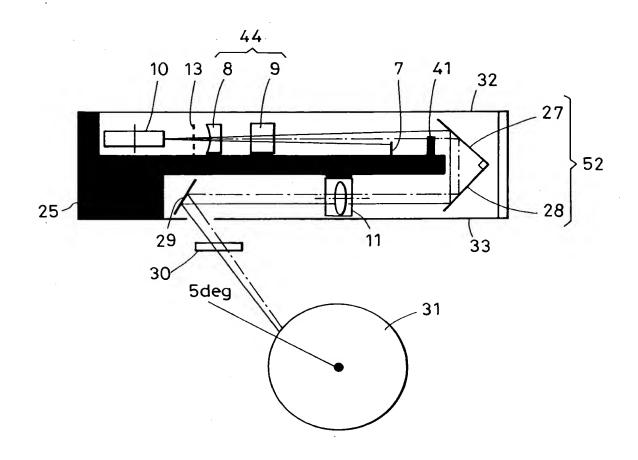


FIG. 9A

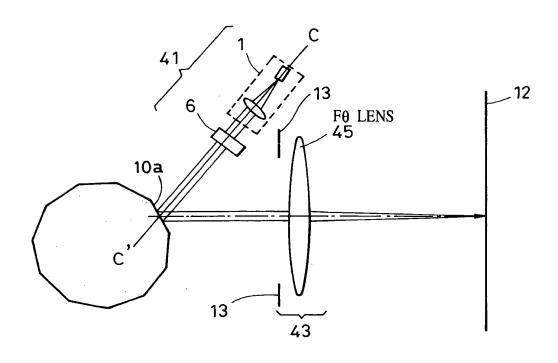


FIG. 9B

## SECTION IN SUB-SCAN OPERATION TAKEN ALONG LINE CC

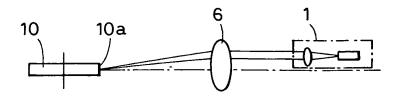
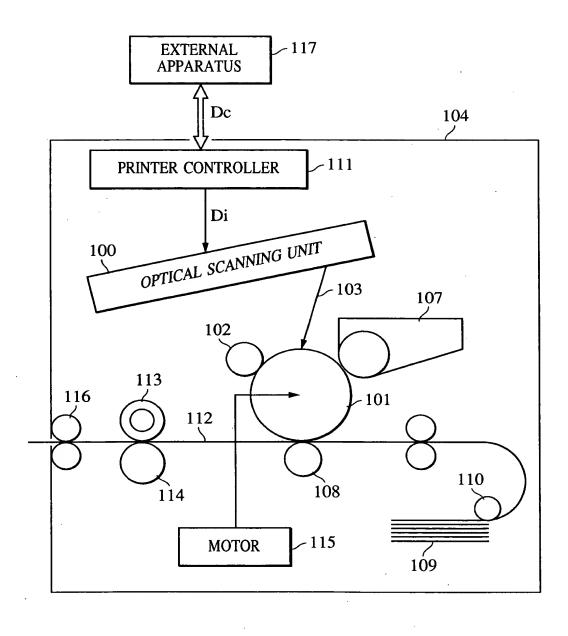


FIG. 10



## FIG. 11

